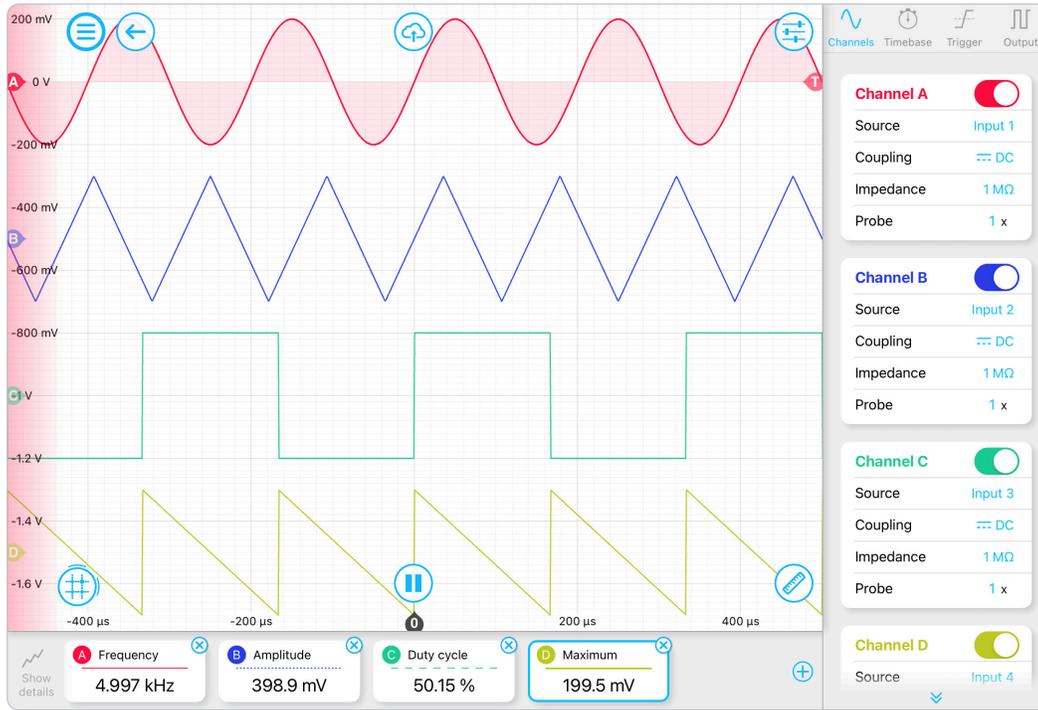




The Moku:Pro Oscilloscope features four high-speed, ultra-low-noise input channels with 600 MHz analog bandwidth. An innovative blended ADC technology combines the information from 10-bit and 18-bit ADCs to cover a broad spectrum, providing class-leading input noise performance at 30nV/√Hz @ 100Hz with large dynamic range. The built-in four-channel Waveform Generators are capable of producing waveforms with a bandwidth of up to 500 MHz.



|                                       |                             |                                       |                                       |   |   |
|---------------------------------------|-----------------------------|---------------------------------------|---------------------------------------|---|---|
| <b>Sampling Rate</b><br>Up to 5 GSa/s | <b>Bandwidth</b><br>600 MHz | <b>ADC Resolution</b><br>10 / 18 bits | <b>Input Impedance</b><br>50 Ω / 1 MΩ | <b>Input Noise</b><br>30 nV/√Hz @ 100Hz | <b>Waveform Generator</b><br>4 Channels up to 500 MHz |
|---------------------------------------|-----------------------------|---------------------------------------|---------------------------------------|---|---|

## Features

- Four analog inputs with 600 MHz bandwidth
- Exceptional low-frequency noise performance: 30 nV/√Hz @ 100 Hz
- Dual-ADC design with blended ADC technology
- Ultra stable 0.3 ppm onboard oscillator with 10 MHz synchronization in and out
- Integrated high-speed waveform generator channels with analog bandwidths up to 500 MHz

## Specifications

- Input range: 400 mVpp, 4 Vpp, or 40 Vpp
- Input noise: 30 nV/√Hz @ 100 Hz
- Sampling rate: 5 GSa/s on 1 channel  
1.25 GSa/s on 4 channels
- Input bandwidth: 300/600 MHz switchable
- Input coupling: AC or DC
- Input Impedance: 50 Ω or 1 MΩ
- Output bandwidth: 500 MHz (2 Vpp)  
100 MHz (10 Vpp)
- Output waveforms: sine, square, ramp, pulse, DC
- Math channel: Add, subtract, multiply, divide, XY mode, integrate, differentiate, FFT, min hold, max hold, and equation editor

## Applications

- Automated system test
- Circuit design and characterization
- Jitter/clock analysis
- Photo detector alignment
- Signal monitoring and analysis
- System test and debug